ON Semiconductor



Test Procedure for the LV5636VHGEVB Evaluation Board

The following steps detail the basic test procedure for all these boards:

Suggested equipment:

• Current limited DC Power Supply (e.g. ADVANTEST R6243 DC Voltage Current Source/Monitor) ···· 2pcs
• Digital Multimeter (e.g. ADVANTEST R6452 Digital Multimeter) 2pcs
• Multifunction Generator (e.g. NF WF1974) ······ 2pcs
• Electronic Load (e.g. FUJITSU ACCESS LIMITED Electric Load EUL-150αXL) ······· 1pc
• Oscilloscope (e.g. LeCroy WaveRunner) ····· 1pc

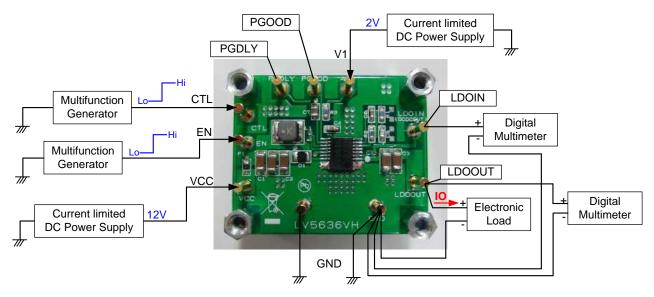


Figure 1: Test Setup

Test Procedure:

- (1) Connect the test setup as shown in Figure 1
- (2) Apply 12Vdc to VCC.
- (3) Apply 2Vdc to V1.
- (4) Apply Low level (0V) or High level (2V) signal to CTL.
- (5) Apply Low level (0V) signal to EN.
- (6) Check that LDOIN=12[V] and LDOOUT=0[V].
- (7) Apply IO(load)=0[A] to LDOOUT.
- (8) Apply High level (2V) signal to EN.
- (9) If CTL state = Low, Check that LDOIN=12.3[V] and LDOOUT=11.7[V] If CTL state = High, Check that LDOIN=16.5[V] and LDOOUT=15.9[V]
- (10) Set IO to desired level, 0[mA] 410[mA], and measure LDOOUT voltage and LDOIN voltage.
- (11) Change CTL level to High or Low. And Confirm (9) and (10).
- (12) Apply Low level signal to EN.
- (13) Turn off IO(load).
- (14) Turn off VCC, V1, CTL and EN.